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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.: 10/695,336

Applicant(s): Geiss et al.

Filed.: October 28, 2003

Art Unit: 2813

Dkt. No.: BUR920010184US2

Examiner: Nema O. Berezny

Title: METHOD OF CONTROLLING GRAIN SIZE IN A POLYSILICON LAYER AND
IN SEMICONDUCTOR DEVICES HAVING POLYSILICON STRUCTURES

*Fee
only*

Honorable Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

REQUEST FOR RECONSIDERATION

This Request for Reconsideration is being filed in response to the Office Action mailed on April 20, 2005. Applicants request this Amendment be entered in the above-identified application and reconsideration of the application in view of the Amendments and Remarks that follow.

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CONCLUSION

Based on the preceding arguments, Applicants respectfully believe that all pending claims and the entire application meet the acceptance criteria for allowance and therefore request favorable action. If Examiner believes that anything further would be helpful to place the application in better condition for allowance, Applicants invite the Examiner to contact the Applicants' representative at the telephone number listed below. The Director is hereby authorized to charge and/or credit Deposit Account 09-0456.

Respectfully submitted,
FOR: Geiss et al.

Dated: 07/05/2005

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